

**Search Notes****Application/Control No.**

09/396,244

**Examiner**

Cheukfan Lee

**Applicant(s)/Patent under Reexamination**

NAGANO, MASATOSHI

**Art Unit**

2625

**SEARCHED**

Class	Subclass	Date	Examiner
358	487,506, 475,509	10/26/2006	C.L.
	512-514		
	482,483		
	484		
	504,406		
	474,496		
	463,505		
399	211,212		
355	30,40,41		
	67-71		
250	208.1		
	330,332		
	234-236		
382	318,319		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search: terms include: (IR infrared (infra adj red) invisible (non adj visible) UV (ultra adj violet)) with		
(search terms cont.): (dust\$2 scratch\$3 (foreign adj (object matter)) contamina\$6 defect\$2 flaw)		
Edgar (5,266,805), col. 15, lines 37-46		
Inventor search		
Obviousness-type double patenting considered: between this application and 10/974,522		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
358	475,487		
	506,509		